

FPGA Based Testing of Hybrid Real-time Systems

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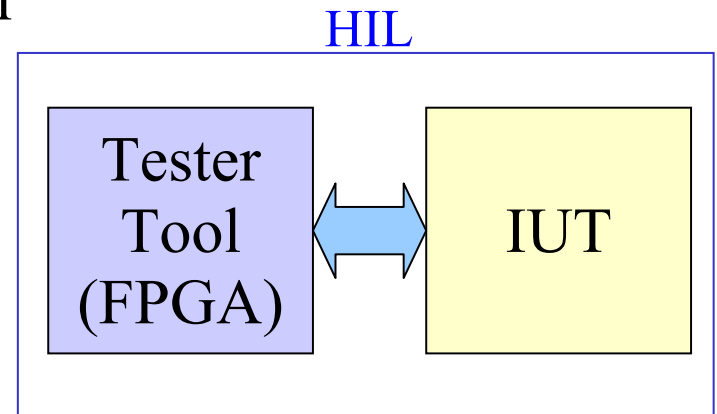


Outline

- Introduction
- Motivation
- Tester tool structure
- Implementation
 - Continuous system
 - Discrete event system
- Case study
- Conclusion

Introduction

- Hardware-In-the-Loop (HIL)
 - Implementation Under Test (IUT)
 - technology process controller
 - automotive ECU, etc.
 - **Tester tool**
 - System model
 - Tester – case generator
 - Interfaces (verification I/O, HW I/O etc.)



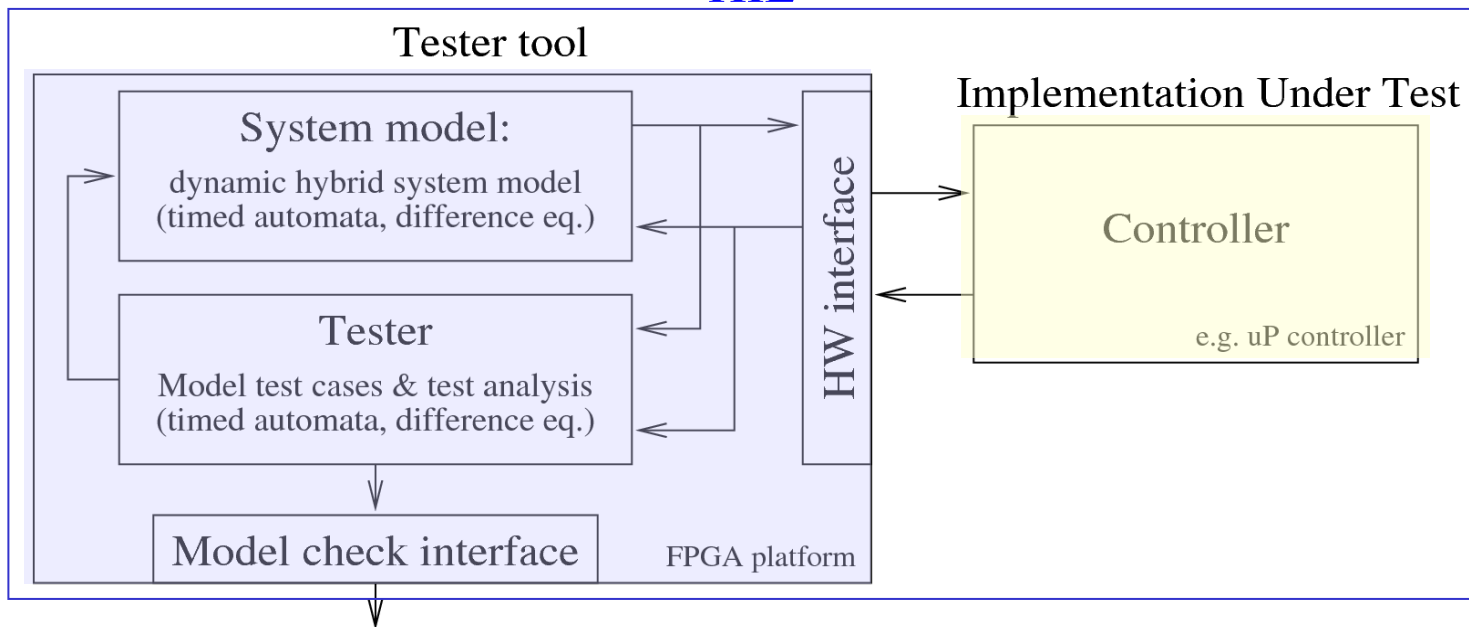
Motivation

- **New design methodology of TT**
 - **continuous** system (difference equation)
 - **discrete event** system (**timed automata**)
 - simple design
 - **verification using temporal logic**
 - **model checking**
 - logical, timed properties, deadlock free detection etc.
 - **FPGA platform use**
 - **speed** performance, **extensibility**, **time accuracy**
 - not influenced by upper layers (e.g. OS services)

Tester tool structure

- System model
 - system specification
- Tester
 - Case generator
 - Analyzer
- HW interface
 - e.g. PWM, IRC
- MC interface

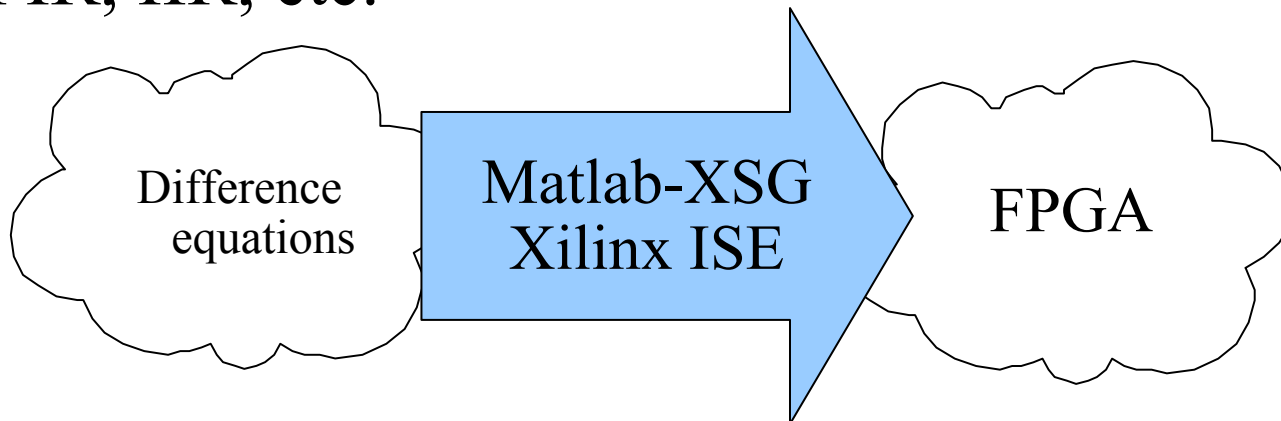
HIL



Property satisfied: TRUE / FALSE

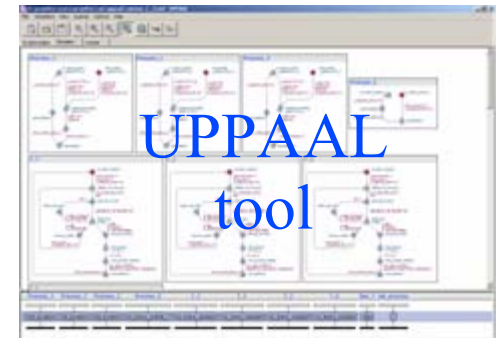
Continuous system implementation

- Discrete-time system
 - Difference equation
 - filter design and signal processing [Lutovac00]
- equation implementation $\Rightarrow$ FPGA
 - FIR, IIR, etc.

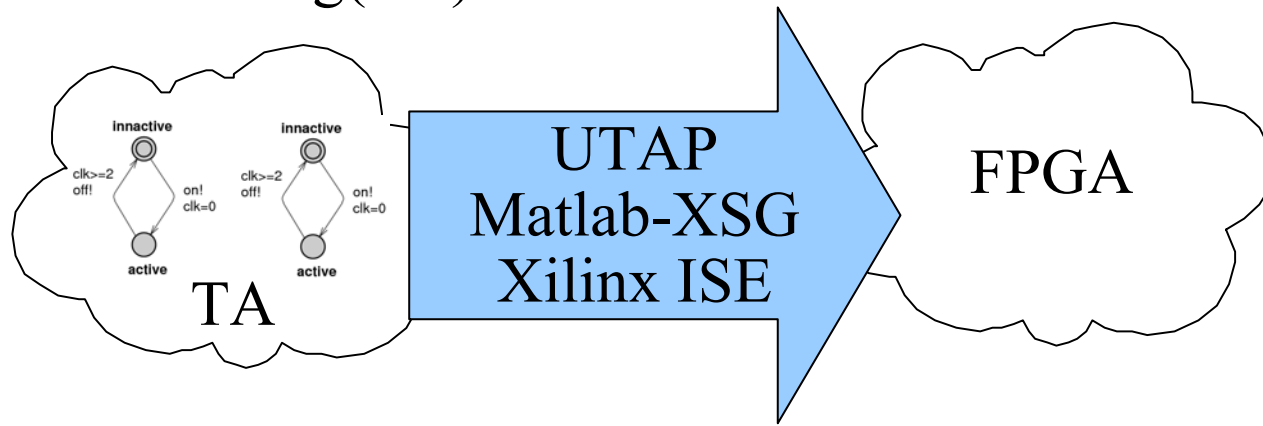


Discrete event system implementation

- Timed automata [Alur 94]
 - UPPAAL tool [Uppaal 02]
 - Verification using CTL

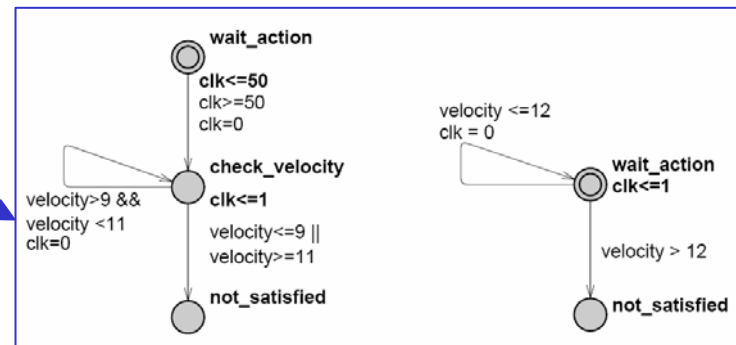
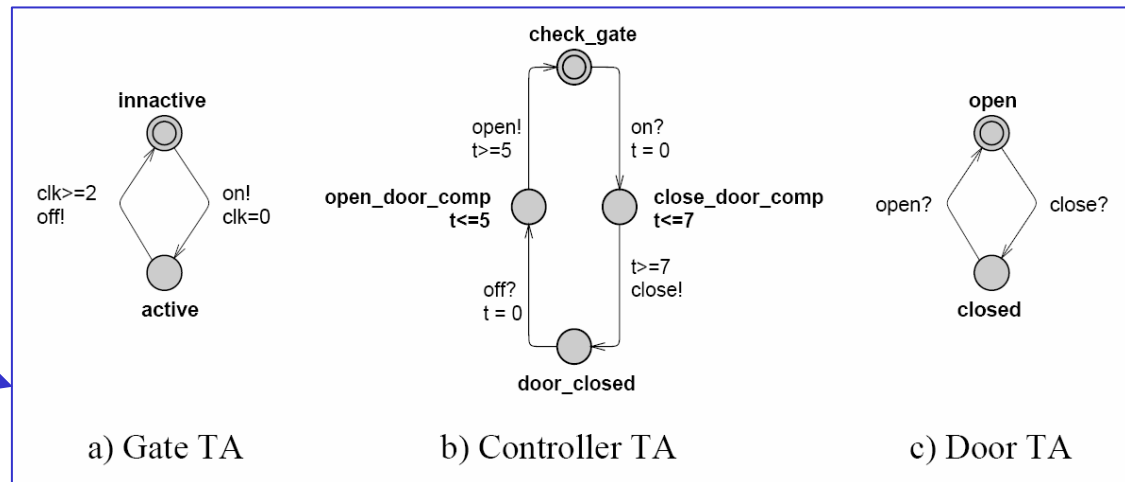


- Implementation $TA \Rightarrow FPGA$ [Tripakis 05]
 - $TA \Rightarrow Prog(TA)$



Discrete event system implementation

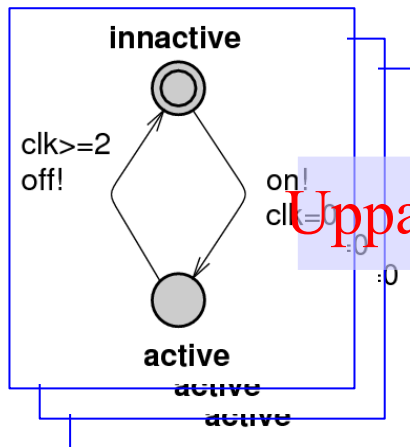
- Why timed automata?
 - Discrete event system behavior description
 - Designing of observers for a tester
 - TA verification



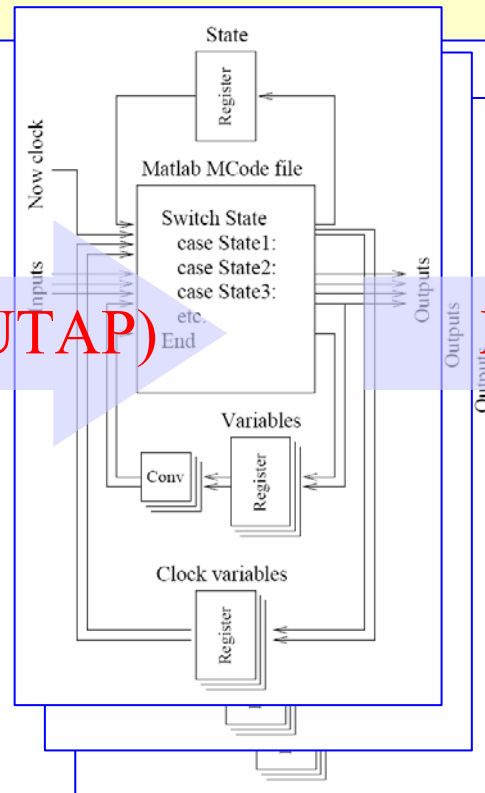
Discrete event system implementation

UPPAAL

Matlab/Simulink, Xilinx System generator



Uppaal2m (C++, UTAP)



Xilinx ISE



Case study – servo-system

- **Servo-system**
 - **without friction** to the shaft
 - **with friction**
- **Two controllers** to be tested

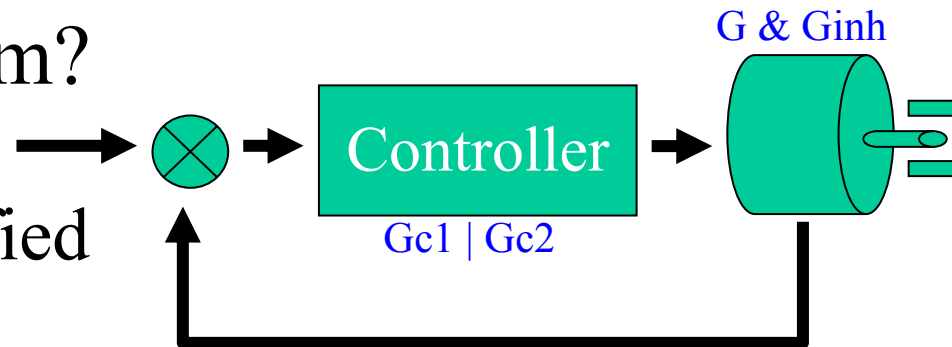
$$G(z) = \frac{2.652z + 0.3143}{z^2 - 0.9202z + 0.0001003}$$

$$G_{inh}(z) = \frac{2.559z + 0.2924}{z^2 - 0.8483z + 9.249 * 10^{-5}}$$

$$G_{C1}(z) = \frac{0.3136}{z + 0.5151}$$

$$G_{C2}(z) = \frac{0.3377z - 0.3056}{z - 1}$$

- Are given controllers able to control such system?
 - Test cases
 - Properties to be verified



Case study – servo-system

- Test cases
 - $[0; 20)$ msec – motor with no friction
 - $[20; \text{inf})$ msec – motor with a friction

- Controller properties to be verified

Property 1:

The motor **angular velocity in interval (9,11) Rads-1 within 5 msec**

For test case 1 only

Property 2:

The motor **angular velocity in interval (9,11) Rads-1 within 5 msec**

For test case 2 only

Property 3:

The motor **angular velocity does not exceed 12 Rads-1**

For test case 1 and 2 as well

Case study – servo-system

- Tester tool structure

Motor behavior
Continuous system

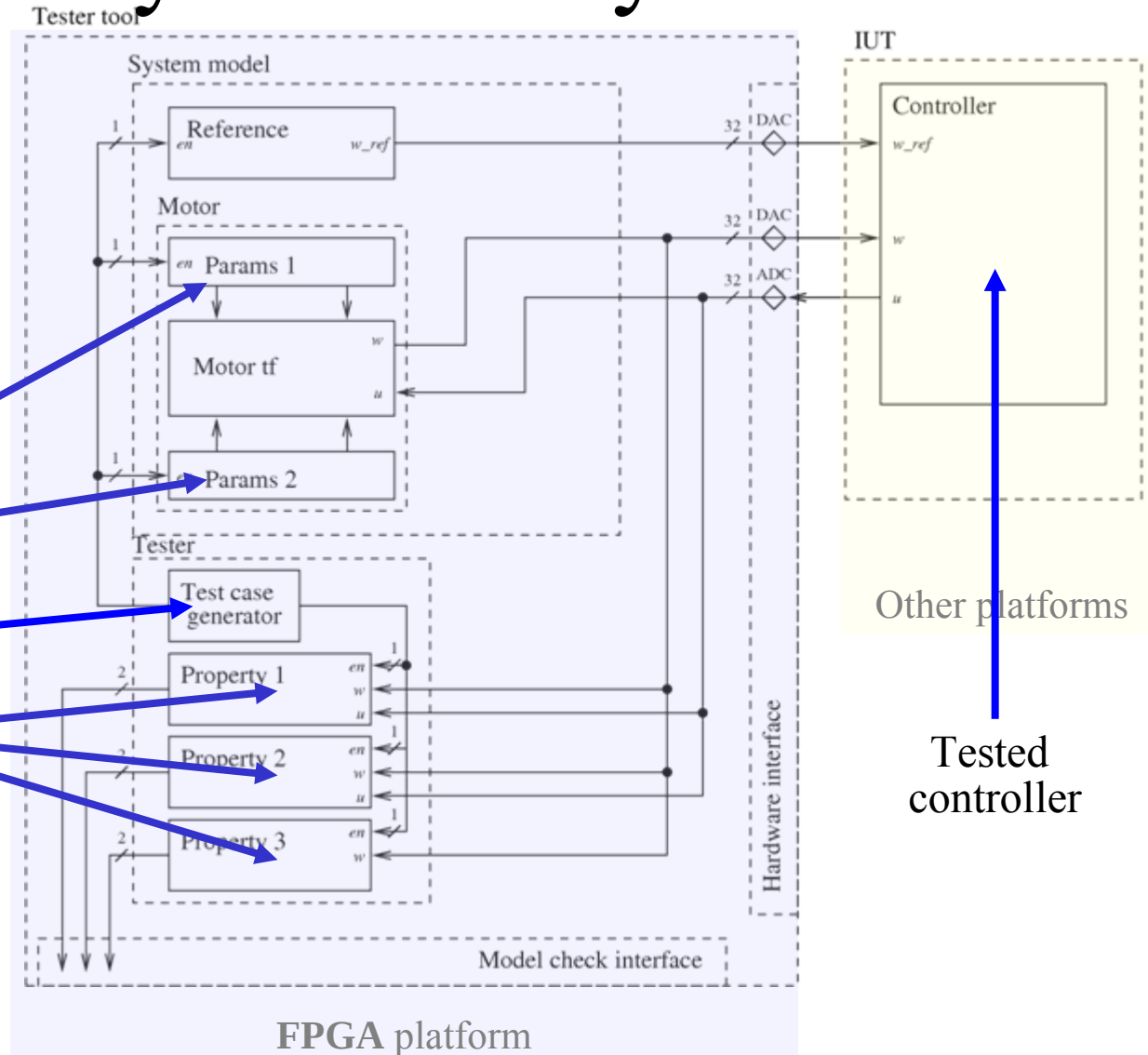
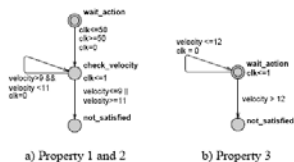
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$$G_{inh}(z) = \frac{2.559z + 0.2924}{z^2 - 0.8483z + 9.249 \cdot 10^{-5}}$$

Test case

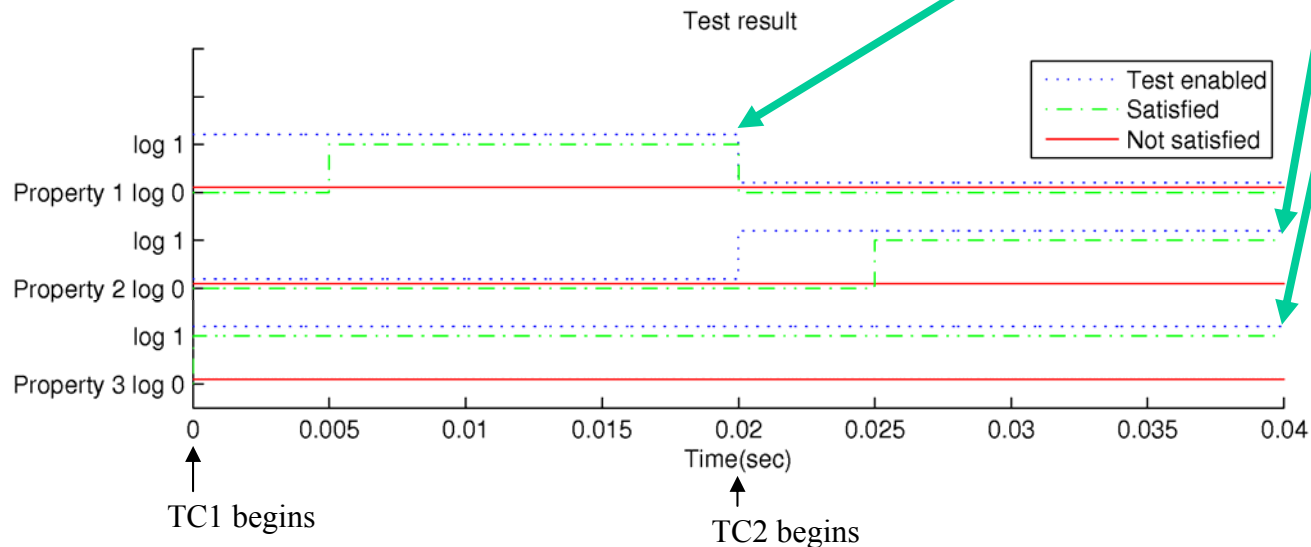
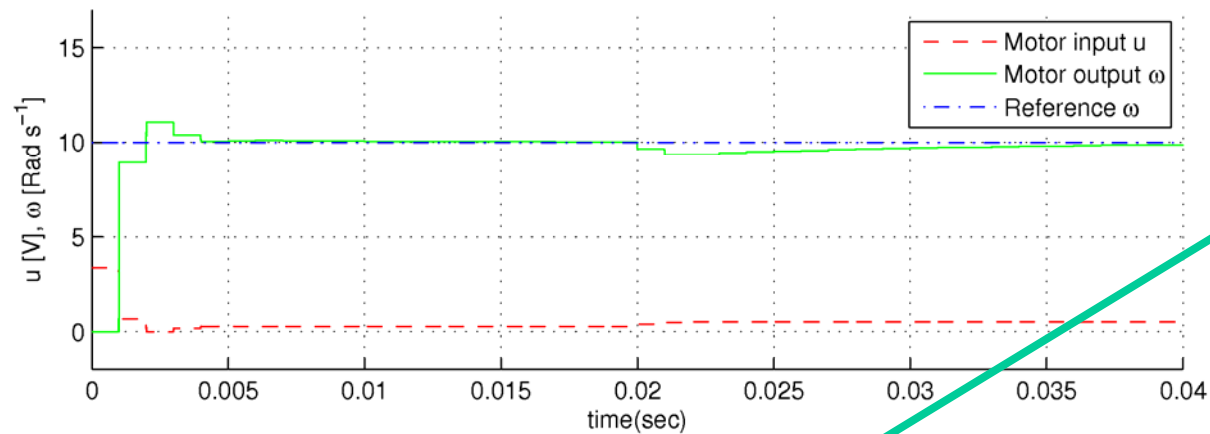
Properties to be verified

Discrete event system



Case study – servo-system

Controller 1 test results



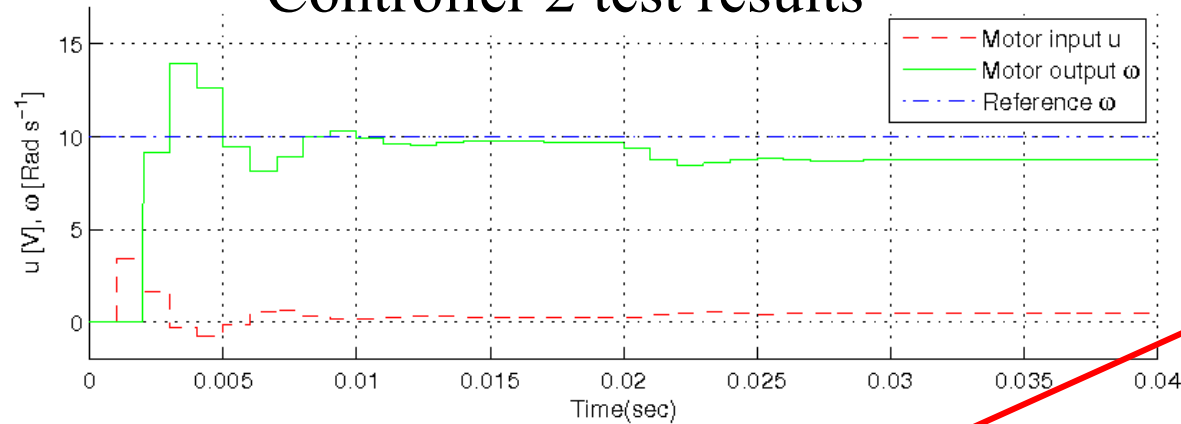
Property 1 - Satisfied

Property 2 - Satisfied

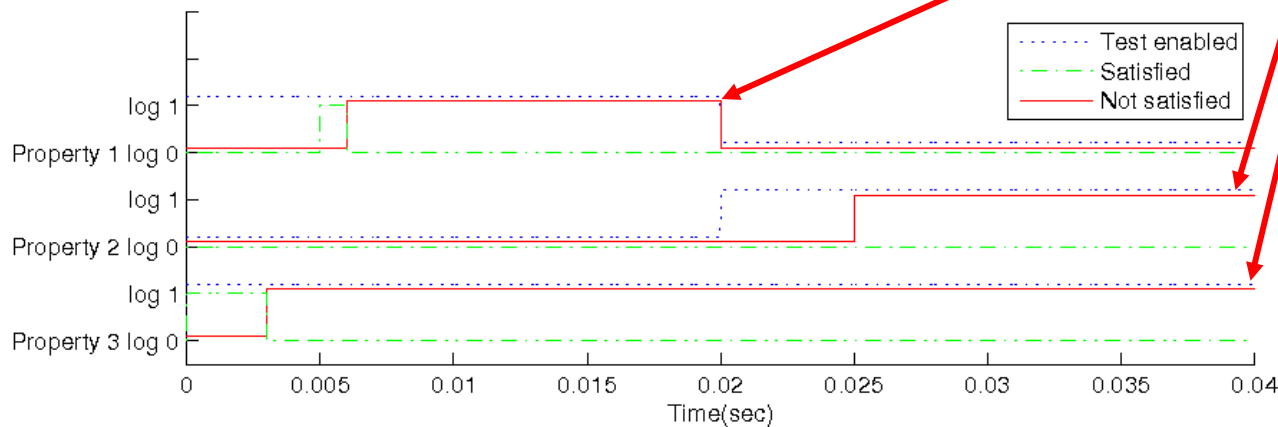
Property 3 - Satisfied

Case study – servo-system

Controller 2 test results



Test result



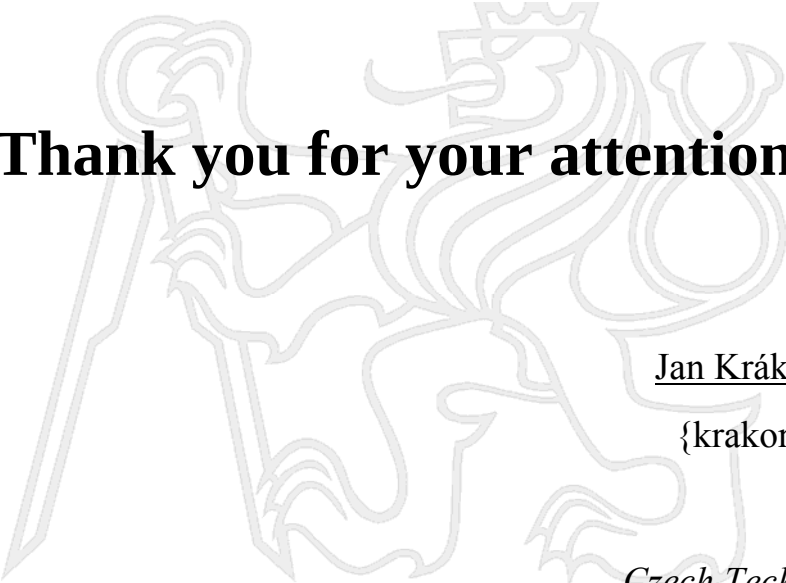
Property 1 – Not satisfied

Property 2 – Not satisfied

Property 3 – Not satisfied

Conclusion & Further work

- Conclusion
 - **New design methodology of TT** into FPGA
 - High sampling period (nsec), Low jitter, Scalability, High degree of parallelism
 - **DES** based on **timed automata**
 - Testing framework speed performance
 - 100nsec (in compare to OS based testers)
- Further work
 - **Hardware interface improvement**
 - DAC/ADC, PWM, IRC etc.
 - **Dynamic reconfiguration of FPGA**
 - on-line generation of test cases
 - automation of testing process
 - Transformation tool improvement



Thank you for your attention

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